

PRODUCT BULLETIN # 20251

Generic Copy

Issue Date: 08-Oct-2013

TITLE: Datasheet change for NE5532-D

PROPOSED FIRST SHIP DATE: 08-Oct-2013

AFFECTED CHANGE CATEGORY(S): Datasheet revision

FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:

Contact your local ON Semiconductor sales office or <Juraj.Frohlich@onsemi.com>

NOTIFICATION TYPE:

ON Semiconductor considers this change approved unless specific conditions of acceptance are provided in writing. To do so, contact <quality@onsemi.com>.

DESCRIPTION AND PURPOSE:

ON Semiconductor is notifying about a data sheet revision for the NE5532-D. As a result of additional device characterization, the input bias current (IB) parameter at room temperature is going to be corrected. Typical value of the IB parameter will be changed from current 200nA to 300nA for all device versions and there will be corrected also IB Max limit from 400nA to 500nA for the SE5532/A version.

			SE5532/A			NE5532/A, SA5532			
Characteristic	Symbol	Test Conditions	Min	Тур	Max	Min	Тур	Max	Unit
				300	500		300		
Input Current	I _B	-	-	-200-	400	-	200 -	800	nA
	-	Overtemperature	-	-	700	-	-	1000	nA
	$\Delta I_B/\Delta T$	-	-	5.0	-	-	5.0	-	nA/°C

List of affected Parts:

SE5532AD8G SE5532AD8R2G SE5532NG

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If no Customer Part Number is on file, the CPN Part Number is marked "CPN Unassigned".

MPN	CPN	Company Name	Company Code	Division Name	Division Code
SE5532AD8G	1426383	PREMIER FARNELL	mm	FARNELL ELEC COMPS	FANRZ